## Notice of References Cited Application/Control No. 10/577,110 Applicant(s)/Patent Under Reexamination KETELAARS ET AL. Examiner RICHARD M. BEMBEN Applicant(s)/Patent Under Reexamination KETELAARS ET AL. Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-7,133,068	11-2006	Fisher et al.	348/218.1
*	В	US-6,009,190	12-1999	Szeliski et al.	382/154
*	С	US-2001/0045986	11-2001	Edwards, Eric D.	348/239
*	D	US-2004/0189849	09-2004	Hofer, Gregory V.	348/333.03
*	Е	US-6,304,284	10-2001	Dunton et al.	348/36
*	F	US-6,456,323	09-2002	Mancuso et al.	348/218.1
*	G	US-6,466,262	10-2002	Miyatake et al.	382/284
*	Н	US-6,466,701	10-2002	Ejiri et al.	382/284
*	I	US-7,428,007	09-2008	Kitaguchi et al.	348/218.1
*	J	US-5,689,611	11-1997	Ohta et al.	386/46
*	К	US-5,721,624	02-1998	Kumashiro et al.	358/450
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Ø					
	R					
	Ø					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	W	
	×	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.